

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/702,572	CERN, YEHUDA		
Examiner	Art Unit		
Nam V. Nauvan	2612		

SEARCHED					
Class	Subclass	Date	Examiner		
340	310.01	1/28/2008	NN		
340	310.05	1/28/2008	NN		
340	310.07	1/28/2008 NN			
340	506,532	1/28/2008	NN		
375	267	1/28/2008	NN		
375	295	1/28/2008	NN		
375	200	1/28/2008	NN		
324	601	1/28/2008	NN		
455	63	1/28/2008	·NN		
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
ABOVE	1/28/2008	NN			
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	Subclass	Subclass Date			

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Search East: USPAT; US-PUB; EPO; JPO and Derwent. (updated search)	1/28/2008	NN
Consulted with Benjamin Lee	3/6/2007	NN
Search Term: plcs/plc/plcc; electromagnetic radiaion intensity; modem; agc/sensor; frequency band adjust power frequencies	1/28/2008	NN
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